

~~Subcl.~~ **IN THE CLAIMS:**

~~B1~~ 1. (Twice Amended) A probe apparatus for testing a circuit chip, said probe apparatus comprising a probe group having two or more probes within a guiding boundary for independently conductively contacting a single terminal of said circuit chip and allowing a test path resistance be measured without affecting said circuit chip.

~~B2~~ 2. (Amended) The probe apparatus of claim 1, further comprising an electronic circuit capable of recognizing said test path resistance and correspondingly compensating a voltage drop of an operational signal passing through at least one of said probes.